Product Specification 108-115008

Shield Finger Scalable Height From 1.24mm to 3.4mm

1. SCOPE

1.1. Content

This specification covers the requirements for product performance test methods and quality assurance provisions of the scalable spring finger. Applicable product descriptions and part numbers are as shown in Appendix 1.

1.2. Qualification

When tests are performed on the subject product line, procedures specified in Figure 2 shall be used. All inspections shall be performed using the applicable inspection plan and product drawing.

2. APPLICABLE DOCUMENTS

The following documents form a part of this specification to the extent specified herein. Unless otherwise specified, the latest edition of the document applies. In the event of conflict between the requirements of this specification and the product drawing, the product drawing shall take precedence. In the event of conflict between the requirements of this specification and the referenced documents, this specification shall take precedence.

2.1. Tyco Electronics Documents

501-115009-*: Qualification Test Report

2.2. Commercial Standard and Specifications:

		2.2. Commercia	I Star	idard a	and Specificatio	ns:		
P BY DTHO V A		Test Methods fo	r Elect	ronic C	Component Parts	: MIL-STD-20	02.	
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3. REQUIREMENTS:

3.1. Design and Construction:

Product shall be of the design, construction and physical dimensions specified on the applicable product drawing.

3.2. Materials:

Material used in the construction of this product shall be as specified on the applicable product drawing.

3.3. Ratings

- A. Voltage: 12 volts AC
- B. Current: 0.5A
- C. Temperature: -40 °C to 85 °C

3.4. Performance and Test Description

Product is designed to meet the electrical, mechanical, and environmental performance requirements specified in Figure 1. Unless otherwise specified, all tests shall be performed at ambient environmental conditions.

3.5. Test Requirements and Procedures Summary

Para.	Test Items	Requirements	Procedures
3.5.1	Initial examination of	Meets requirements of	Visual inspection. EIA-364-18.
	Product	product drawing	
3.5.2	Final examination of	Meets visual requirements	Visual inspection. EIA-364-18.
	Product		
		Electrical Requirements	3
3.5.3	Low Level Contact	Initial: 80 m Ω Max.	Subject mated specimens to 20 mV
	Resistance (LLCR)	Final: ΔR 25 m Ω Max.	Max open circuit at 100 mA DC.
			In acc. with IEC 60512-2 test 2a
3.5.4	Temperature Rise	30°C Max. under loaded	The voltage / Current should be
		rating current	applied to the contacts for 1 hours as
			below.
			Voltage: 5V D.C
			Current: 0.7A
		Mechanical Requiremen	ts
3.5.5	Normal Force	Normal Force at nominal	Stroke the spring top to the nominal
		height: 0.60+/-0.2N.	working height
3.5.6	Durability	Normal Force at nominal	No. of cycles: 10 cycles.
		height: 0.60+/-0.2N.	Stroke the spring top to the nominal
		80 milliohms Max. (Initial)	working height
		ΔR 25 milliohms Maximum.	
		(Final)	
		Figure 1 (continued)	

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3.5.7	Shock	No discontinuities of 1	Subject mated specimens to 30G's					
5.5.7		microsecond or longer	half-sine shock pulses of 6					
		duration.	milliseconds duration. Three shocks					
		80 milliohms Max. (Initial)	in each direction applied along 3					
		ΔR 25 milliohms Maximum.	mutually perpendicular planes, 18					
		(Final)	shocks.					
			See Figure 3					
3.5.8	Vibration, Random	No discontinuities of 1	Subject mated specimens at nominal					
		microsecond or longer	working height.					
		duration.	5 Hz 0.1m2/s3					
		80 milliohms Max. (Initial)	12 Hz 2.2 m2/s3					
		ΔR 25 milliohms Maximum.	20Hz 2.2. m2/s3					
		(Final)	200Hz 0.04 m2/s3					
			500Hz 0.04 m2/s3					
			Temperature: 23+/-5°C.					
			Humidity: 35~70%RH.					
			2 hours for X&Y&Z.					
3.5.9	Solderability	Solder wetting time shall be	Refer to JESD22-B102E.					
2.0.0		no more than 3 seconds. A	Lead free soldering.					
		new uniform coating of						
		solder shall cover a minimum						
		of 95% of the surface being						
		immerged.						
0 5 10	Thermal check	Environment Requirements Initial: 80 m Ω Max.	Cubicat material analysis of a series					
3.5.10	Thermal shock		Subject mated specimen at nominal					
		Final: ΔR 25 m Ω Max.	working height to 256 cycles between -40 and 85°C with 30 minute dwells					
			including 0~5 minute transition time.					
			See Figure 6.					
3.5.11	Heat test	Initial: 80 m Ω Max.	Subject mated specimen at nominal					
	(non operational)	Final: ΔR 25 m Ω Max.	working height to 85+/-3 °C, 50+/-					
			5%RH, 16h. See Figure 4					
3.5.12	Cold test	Initial: 80 m Ω Max.	Subject mated specimen at nominal					
	(non operational)	Final: ΔR 25 m Ω Max.	working height to -40+/-3 °C, 16h.					
			See Figure 5.					
3.5.13	Heat test	Initial: 80 m Ω Max.	Subject mated specimen at nominal					
	(operational)	Final: ΔR 25 m Ω Max.	working height to test condition as					
			Figure 7.					
3.5.14	Cold test	Initial: 80 m Ω Max.	Subject mated specimen at nominal					
	(operational)	Final: ΔR 25 m Ω Max.	working height to test condition as					
			Figure 8.					
		Figure 1 (continued)						
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3.5.15	Condensation test-	Initial: 80 mΩ Max.	Subject mated specimen at nominal
	operational	Final: ΔR 25 m Ω Max.	working height to test condition as
			Figure 9.
3.5.16	Sulfuration for gold	No physical damage shall	Subject mated specimens to the
	surface	occur.	environment:
		Initial: 80 m Ω Max.	H2S: 3ppm
		Final: ΔR 25 m Ω Max.	Temperature: 40+/-2°C
			Humidity: 75+/-3 %
			Duration: 24h
3.5.17	Peeling off strength	2N minimum in vertical to	Subject soldered specimens to the
		PCB direction.	test condition as
		15N minimum in Long pad	Figure 10(vertical to PCB direction)
		direction.	Figure 11(Long pad direction)
		10N minimum in Short pad	Figure 12(Short pad direction)
		direction.	
3.5.18	Resistance to re-flow	No physical damage shall	Subject specimens to reflow process
	soldering heat	occur.	for 3 times per IPC/JEDEC J-STD-20
			table 5-2.
			Moisture sensitivity should meet at
3.5.19	Vibration Sinusoidal	No discontinuities of 1	Moisture sensitivity should meet at lease level 2 per IPC/JEDEC J-STD- 20, table 5-1.
3.5.19	Vibration Sinusoidal	No discontinuities of 1 microsecond or longer	Moisture sensitivity should meet at lease level 2 per IPC/JEDEC J-STD- 20, table 5-1.
3.5.19	Vibration Sinusoidal		Moisture sensitivity should meet at lease level 2 per IPC/JEDEC J-STD- 20, table 5-1. Subject mated specimens at nominal
3.5.19	Vibration Sinusoidal	microsecond or longer	Moisture sensitivity should meet at lease level 2 per IPC/JEDEC J-STD- 20, table 5-1. Subject mated specimens at nominal working height to sinusoidal vibration
3.5.19	Vibration Sinusoidal	microsecond or longer duration.	Moisture sensitivity should meet at lease level 2 per IPC/JEDEC J-STD- 20, table 5-1. Subject mated specimens at nominal working height to sinusoidal vibration over a specified frequency range of 10~500Hz. The X, Y and Z axes of
3.5.19	Vibration Sinusoidal	microsecond or longer duration. 80 milliohms Max. (Initial)	Moisture sensitivity should meet at lease level 2 per IPC/JEDEC J-STD- 20, table 5-1. Subject mated specimens at nominal working height to sinusoidal vibration over a specified frequency range of
3.5.19	Vibration Sinusoidal	microsecond or longer duration. 80 milliohms Max. (Initial) ΔR 25 milliohms Maximum.	Moisture sensitivity should meet at lease level 2 per IPC/JEDEC J-STD- 20, table 5-1. Subject mated specimens at nominal working height to sinusoidal vibration over a specified frequency range of 10~500Hz. The X, Y and Z axes of the mated samples are subjected to 5
3.5.19	Vibration Sinusoidal	microsecond or longer duration. 80 milliohms Max. (Initial) ΔR 25 milliohms Maximum.	Moisture sensitivity should meet at lease level 2 per IPC/JEDEC J-STD- 20, table 5-1. Subject mated specimens at nominal working height to sinusoidal vibration over a specified frequency range of 10~500Hz. The X, Y and Z axes of the mated samples are subjected to 5 sweep cycles/axis.

Figure 1

Shall meet visual requirements, show no physical damage, and meet requirements of additional tests as specified in the Product Qualification and Requalification Test Sequence shown in Figure 2.

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					Test	grou	p				
Test Items	1	2	3	4	5	6	7	8	9	10	11
					Test s	equer	nce				
Initial examination of product	1	1	1	1	1	1	1	1	1	1	1
Terminal resistance (LLCR)		3,6	2,4,6		2,4,6	2,4	2,4		2,5	2,4	
Contact force measurement	4,6										
Durability	5	4									
Shock, Operational										3	
Vibration, Random			3								
Vibration, Sinusoidal			5								
Temperature rise								2			
Solderability				2							
Cold test-non operation					5						
Heat test-non operation					3						
Cold test-Operation									4		
Heat test-Operation									3		
Condensation test-Operation		5									
Sulfuration for gold surface							3				
Thermal shock						3					
Resistance to soldering heat	2	2									
Peeling off											2
Final examination of product	3,7	7	7	3	7	5	5	3	6	5	3

3.6. Product Qualification and Requalification Test Sequence

(a) Numbers indicate sequence in which tests are performed.

(b) Precondition specimens with 10 durability cycles.





















Figure 12



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The applicable products description and part numbers are as shown in appendix 1.

Part Number	Description	Qualification Test
1551631-4	Spring Finger 124	501-115009
1551572-4	Spring Finger 1.80	501-115009-1
1551573-4	Spring Finger 2.15	501-115009-2
1551574-4	Spring Finger 2.60	501-115009-3
1551575-4	Spring Finger 3.0	501-115009-4
1551575-7	Spring r inger 5.0	501 115007 4
1551576-4	Spring Finger 3.4	501-115009-5

Appendix 1

4. QUALITY ASSURANCE PROVISIONS

4.1. Qualification Testing

A. Specimen Selection

Specimens shall be prepared in accordance with applicable Instruction Sheets and shall be selected at random from current production. Each test group shall consist of a minimum of 5 specimens.

B. Test Sequence

Qualification inspection shall be verified by testing specimens as specified in Figure 1.

4.2. Requalification Testing

If changes significantly affect form, fit or functions are made to the product or manufacturing process, product assurance shall coordinate requalification testing, consisting of all or part of the original testing sequence as determined by development/product, quality and reliability engineering.

4.3. Acceptance

Acceptance is based on verification that the product meets the requirements of Figure 1. Failures attributed to equipment, test setup or operator deficiencies shall not disqualify the product. If product failure occurs, corrective action shall be taken and specimens resubmitted for qualification. Testing to confirm corrective action is required before resubmittal.

4.4. Quality Conformance Inspection

The applicable quality inspection plan shall specify the sampling acceptable quality level to be used. Dimensional and functional requirements shall be in accordance with the applicable product drawing and this specification.

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